

# **Maximum Ratings** (@ $T_A = +25^{\circ}C$ , unless otherwise specified.)

Characteristic	Symbol	Value	Units		
Drain-Source Voltage			$V_{DSS}$	20	V
Gate-Source Voltage			$V_{GSS}$	±8	V
Continuous Drain Current (Note 5) V <sub>GS</sub> = 4.5V	Steady State	$T_A = +25$ °C $T_A = +70$ °C	I <sub>D</sub>	510 410	mA
	t<10s	$T_A = +25$ °C $T_A = +70$ °C	I <sub>D</sub>	610 490	mA
Continuous Drain Current (Note 5) V 1 9V	Steady State	$T_A = +25$ °C $T_A = 70$ °C	I <sub>D</sub>	380 300	mA
Continuous Drain Current (Note 5) V <sub>GS</sub> = 1.8V	t<10s	$T_A = +25$ °C $T_A = +70$ °C	I <sub>D</sub>	450 360	mA
Pulsed Drain Current (Note 6)			I <sub>DM</sub>	800	mA

#### Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	Steady state	P <sub>D</sub>	400	mW
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	р	310	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{\theta JA}$	220	°C/W
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

## Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	20	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current @T <sub>C</sub> = +25°C	I <sub>DSS</sub>	_	_	100	nA	$V_{DS} = 16V, V_{GS} = 0V$	
Zero Gate voltage Drain Current @1c = +25 C		_	_	50		$V_{DS} = 5V$ , $V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 5V$ , $V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	$V_{GS(th)}$	0.4	_	1.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
		_	0.60	0.99	Ω	$V_{GS} = 4.5V, I_D = 100mA$	
	R <sub>DS(ON)</sub>	_	0.75	1.2		$V_{GS} = 2.5V, I_D = 50mA$	
Static Drain-Source On-Resistance		_	0.90	1.8		$V_{GS} = 1.8V, I_D = 20mA$	
		_	1.2	2.4		$V_{GS} = 1.5V, I_D = 10mA$	
		_	2.0	_		V <sub>GS</sub> = 1.2V, I <sub>D</sub> = 1mA	
Forward Transfer Admittance	Y <sub>fs</sub>	180	_	_	mS	V <sub>DS</sub> = 10V, I <sub>D</sub> = 400mA	
Diode Forward Voltage	V <sub>SD</sub>	-	0.6	1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 150mA	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C <sub>iss</sub>	_	27.6	55.2	pF	101/1/	
Output Capacitance	Coss	_	4.0	8.0	pF	$V_{DS} = 16V, V_{GS} = 0V,$ -f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	2.8	5.6	pF	1 - 1.000112	
Total Gate Charge	Qg	_	0.5	_	nC	$V_{GS} = 4.5V, V_{DS} = 10V,$ $I_{D} = 250mA$	
Gate-Source Charge	Qgs	_	0.07	_	nC		
Gate-Drain Charge	$Q_{gd}$	_	0.07	_	nC		
Turn-On Delay Time	t <sub>D(on)</sub>	_	4.0	_	ns	$V_{DD} = 10V, V_{GS} = 4.5V,$ $R_L = 47\Omega, R_G = 10\Omega,$ $I_D = 200\text{mA}$	
Turn-On Rise Time	t <sub>r</sub>	_	3.3	_	ns		
Turn-Off Delay Time	t <sub>D(off)</sub>	_	19.0	_	ns		
Turn-Off Fall Time	t <sub>f</sub>	_	6.4	_	ns		

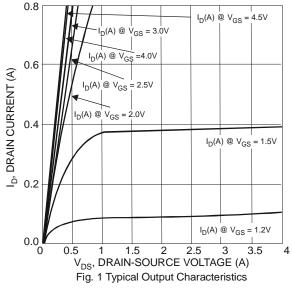
ites: 5. Device mounted on FR-4 PCB, with minimum recommended pad layout.

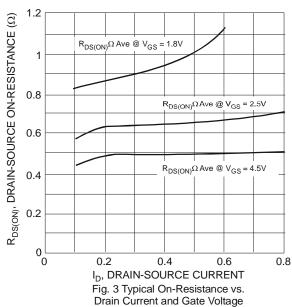
6. Device mounted on minimum recommended pad layout test board, 10µs pulse duty cycle = 1%.

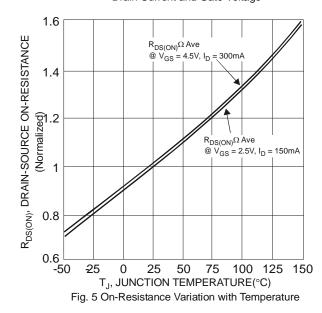
7. Short duration pulse test used to minimize self-heating effect.

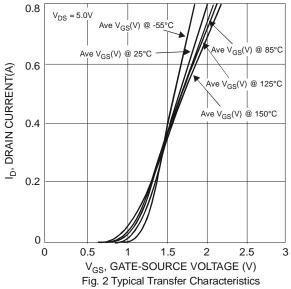
8. Guaranteed by design. Not subject to product testing.











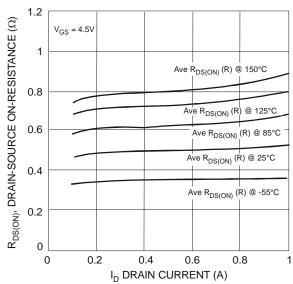


Fig. 4 Typical On-Resistance vs. Drain Current and Temperature

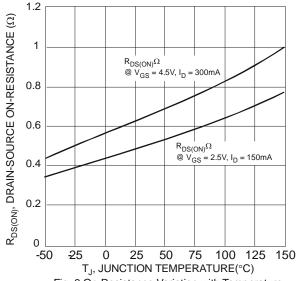


Fig. 6 On-Resistance Variation with Temperature



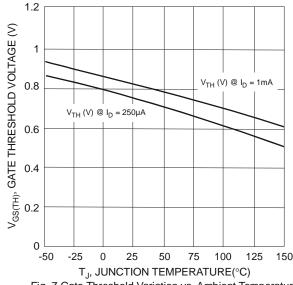
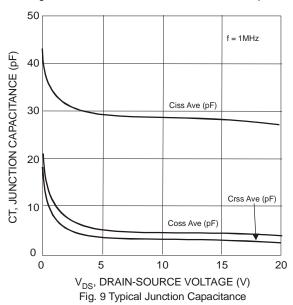
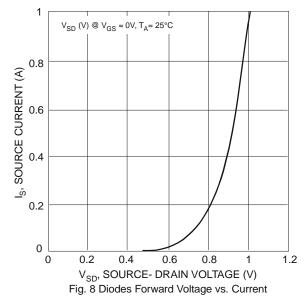


Fig. 7 Gate Threshold Variation vs. Ambient Temperature



8 6 4 2  $V_{DS} = 10V$ 0, 0.4 Q<sub>G</sub> - (nC) 0.2 0.6 0.8

Fig. 11 Gate Charge Characteristics



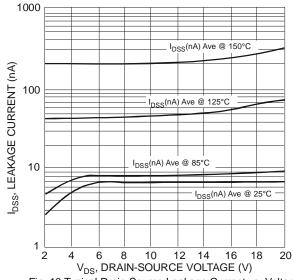
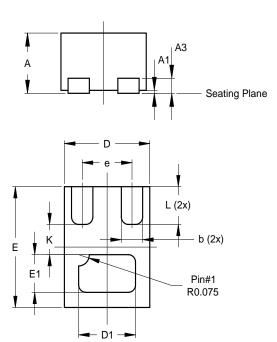


Fig. 10 Typical Drain-Source Leakage Current vs. Voltage



## **Package Outline Dimensions**

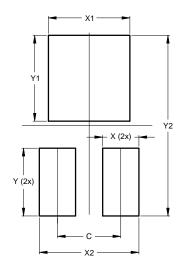
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



X2-DFN0806-3					
Dim	Min	Max	Тур		
Α	0.375	0.40	0.39		
A1	0	0.05	0.02		
A3	-	-	0.10		
b	0.10	0.20	0.15		
D	0.55	0.65	0.60		
D1	0.35	0.45	0.40		
Е	0.75	0.85	0.80		
E1	0.20	0.30	0.25		
е	-	-	0.35		
K	-	-	0.20		
L	0.20	0.30	0.25		
All Dimensions in mm					

## **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value				
Dilliensions	(in mm)				
С	0.350				
Х	0.200				
X1	0.450				
X2	0.550				
Υ	0.375				
Y1	0.475				
Y2	1.000				



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